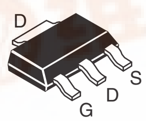
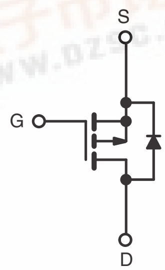
Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	- 100	
$R_{DS(on)}$ (Ω)	V_{GS} = - 10 V	1.2
Q_g (Max.) (nC)	8.7	
Q_{gs} (nC)	2.2	
Q_{gd} (nC)	4.1	
Configuration	Single	

SOT-223





P-Channel MOSFET

FEATURES

- **Halogen-free According to IEC 61249-2-21 Definition**
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- Fast Switching
- Ease of Paralleling
- Compliant to RoHS Directive 2002/95/EC

Available
RoHS*
COMPLIANT
HALOGEN FREE
Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SOT-223 package is designed for surface-mount using vapor phase, infrared, or wave soldering techniques. Its unique package design allows for easy automatic pick-and-place as with other SOT or SOIC packages but has the added advantage of improved thermal performance due to an enlarged tab for heatsinking. Power dissipation of greater than 1.25 W is possible in a typical surface mount application.

ORDERING INFORMATION		
Package	SOT-223	SOT-223
Lead (Pb)-free and Halogen-free	SiHFL9110-GE3	SiHFL9110TR-GE3[a]
Lead (Pb)-free	IRFL9110PbF	IRFL9110TRPbF[a]
	SiHFL9110-E3	SiHFL9110T-E3[a]
SnPb	IRFL9110	IRFL9110TR[a]
	SiHFL9110	SiHFL9110T[a]

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted)

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	- 100	V
Gate-Source Voltage			V_{GS}	± 20	
Continuous Drain Current	V_{GS} at - 10 V	T_C = 25 °C	I_D	- 1.1	A
		T_C = 100 °C		- 0.69	
Pulsed Drain Current[a]			I_{DM}	- 8.8	
Linear Derating Factor				0.025	W/°C
Linear Derating Factor (PCB Mount)[e]				0.017	
Single Pulse Avalanche Energy[b]			E_{AS}	100	mJ
Avalanche Current[a]			I_{AR}	- 1.1	A
Peak Diode Recovery dV/dt[c]			E_{AR}	0.31	mJ
Maximum Power Dissipation		T_C = 25 °C	P_D	3.1	W
Maximum Power Dissipation (PCB Mount)[e]		T_A = 25 °C		2.0	
Peak Diode Recovery dV/dt[c]			dV/dt	- 5.5	V/ns
Operating Junction and Storage Temperature Range			T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s			300[d]	

Notes

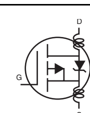
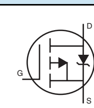
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. V_{DD} = - 25 V, starting T_J = 25 °C, L = 7.7 mH, R_g = 25 Ω, I_{AS} = - 4.4 A (see fig. 12).
c. $I_{SD} \leq$ - 4.4 A, dI/dt $\leq$ - 75 A/μs, $V_{DD} \leq V_{DS}$, $T_J \leq$ 150 °C.
d. 1.6 mm from case.
e. When mounted on 1" square PCB (FR-4 or G-10 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount)[a]	R_{thJA}	-	-	60	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	-	40	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS (T_J = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0 V, I_D = - 250 μA	- 100	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I_D = - 1 mA	-	- 0.091	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = - 250 μA	- 2.0	-	- 4.0	V
Gate-Source Leakage	I_{GSS}	V_{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = - 100 V, V_{GS} = 0 V	-	-	- 100	μA
		V_{DS} = - 80 V, V_{GS} = 0 V, T_J = 125 °C	-	-	- 500	
Drain-Source On-State Resistance	$R_{DS(on)}$	V_{GS} = - 10 V; I_D = - 0.66 A[b]	-	-	1.2	Ω
Forward Transconductance	g_{fs}	V_{DS} = - 50 V, I_D = - 0.66 A	0.82	-	-	S
Dynamic						
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_{DS} = - 25 V, f = 1.0 MHz, see fig. 5	-	200	-	pF
Output Capacitance	C_{oss}		-	94	-	
Reverse Transfer Capacitance	C_{rss}		-	18	-	
Total Gate Charge	Q_g	V_{GS} = - 10 V; I_D = - 4.0 A, V_{DS} = - 80 V, see fig. 6 and 13[b]	-	-	8.7	nC
Gate-Source Charge	Q_{gs}		-	-	2.2	
Gate-Drain Charge	Q_{gd}		-	-	4.1	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = - 50 V, I_D = - 4.0 A, R_G = 24 Ω, R_D = 11 Ω, see fig. 10[b]	-	10	-	ns
Rise Time	t_r		-	27	-	
Turn-Off Delay Time	$t_{d(off)}$		-	15	-	
Fall Time	t_f		-	17	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact 	-	4.0	-	nH
Internal Source Inductance	L_S		-	6.0	-	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 	-	-	- 1.1	A
Pulsed Diode Forward Current[a]	I_{SM}		-	-	- 8.8	
Body Diode Voltage	V_{SD}	T_J = 25 °C, I_S = - 1.1 A, V_{GS} = 0 V[b]	-	-	- 5.5	V
Body Diode Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = - 4.0 A, dI/dt = 100 A/μs[b]	-	80	160	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	0.15	0.30	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

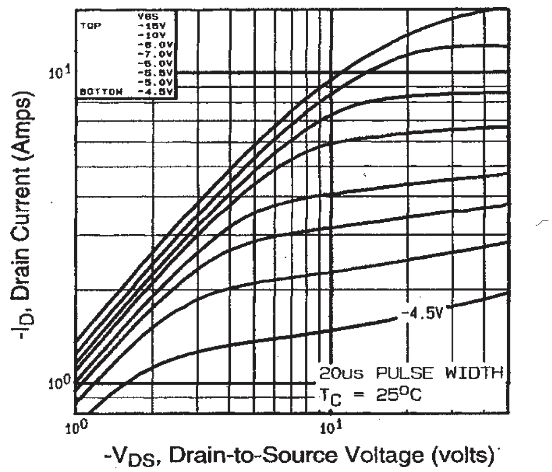


Fig. 1 - Typical Output Characteristics

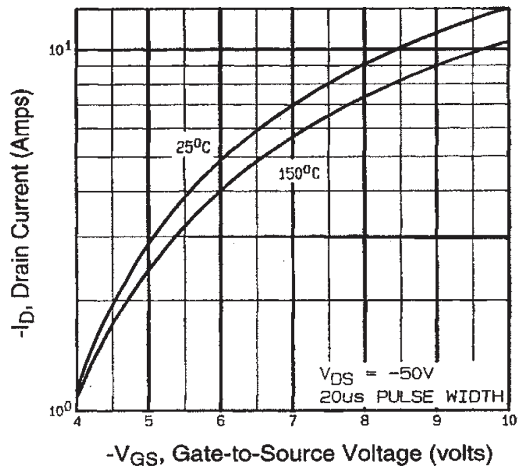


Fig. 3 - Typical Transfer Characteristics

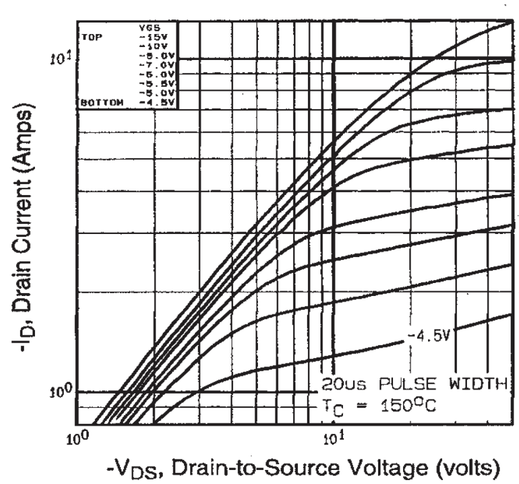


Fig. 2 - Typical Output Characteristics

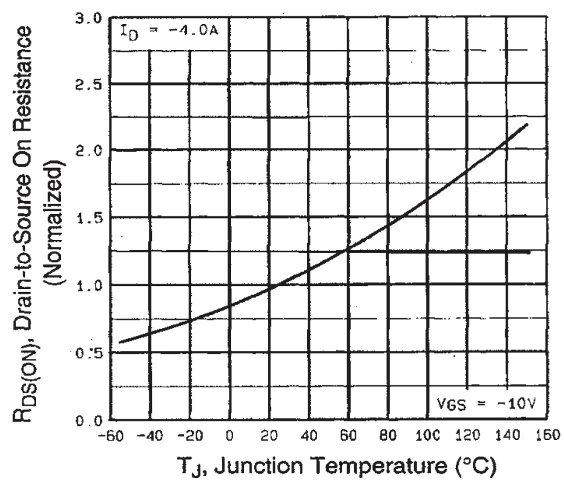


Fig. 4 - Normalized On-Resistance vs. Temperature

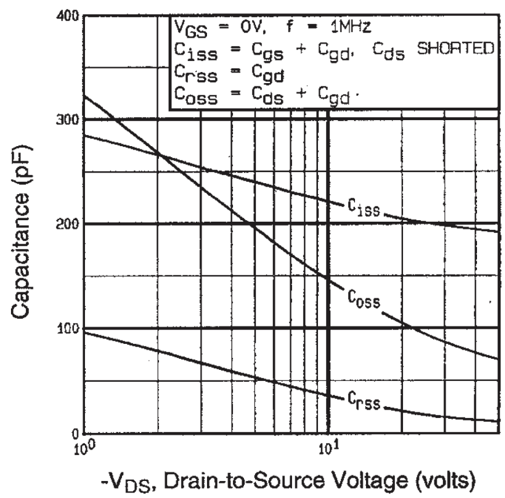


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

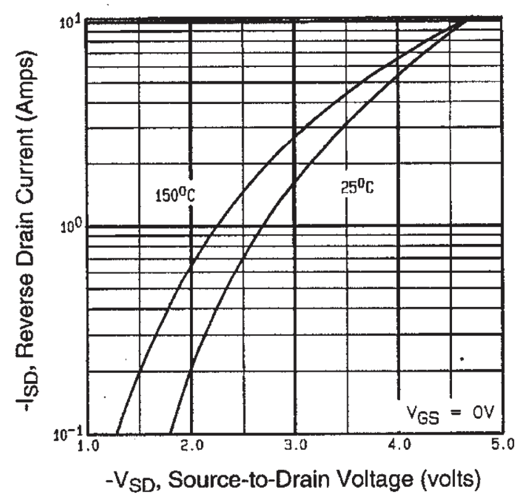


Fig. 7 - Typical Source-Drain Diode Forward Voltage

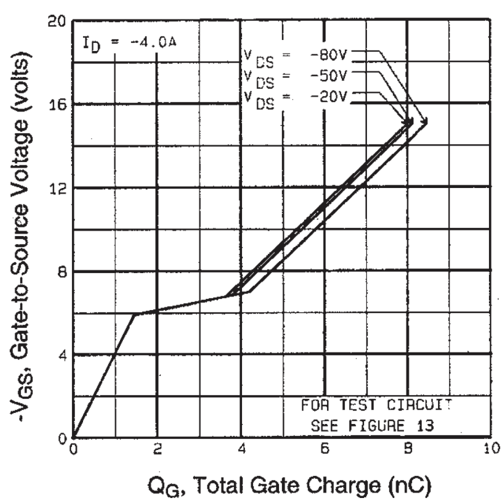


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

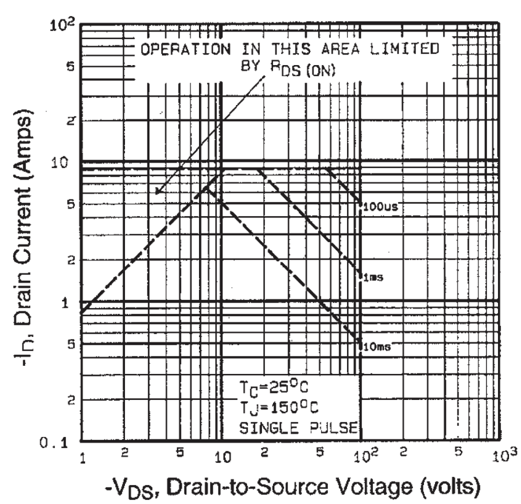


Fig. 8 - Maximum Safe Operating Area

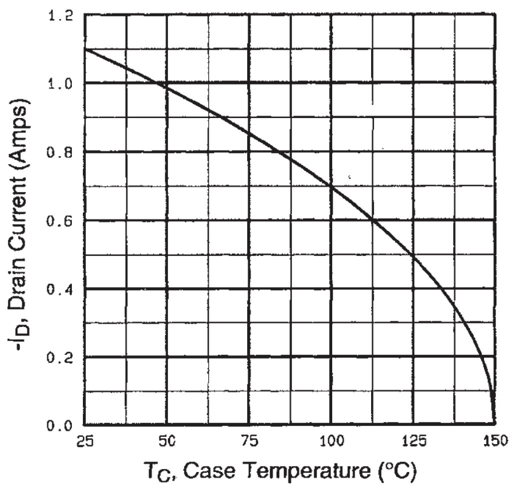


Fig. 9 - Maximum Drain Current vs. Case Temperature

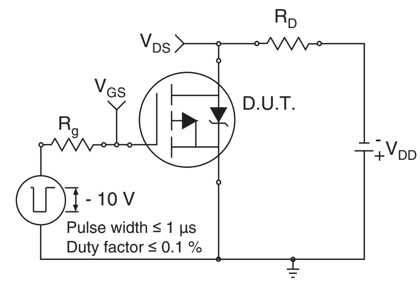


Fig. 10a - Switching Time Test Circuit

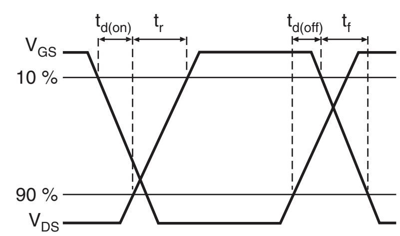


Fig. 10b - Switching Time Waveforms

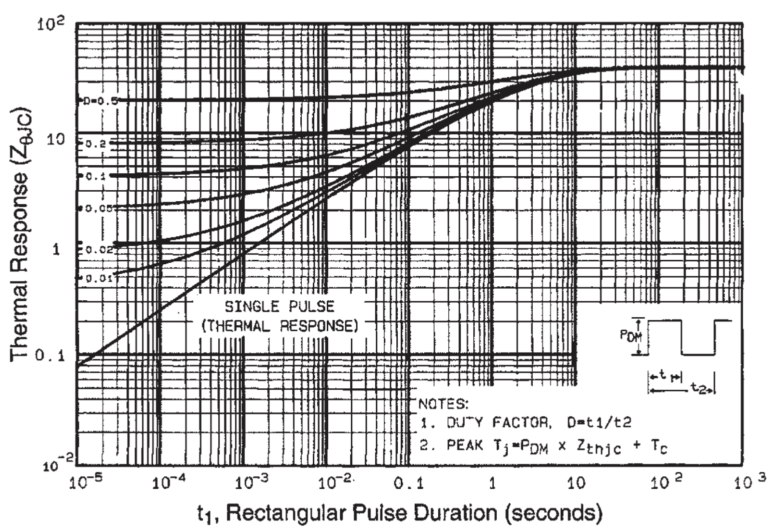


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

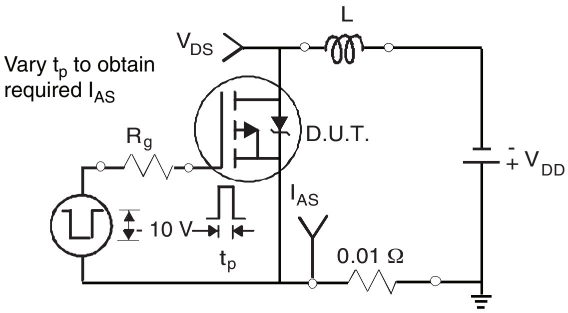


Fig. 12a - Unclamped Inductive Test Circuit

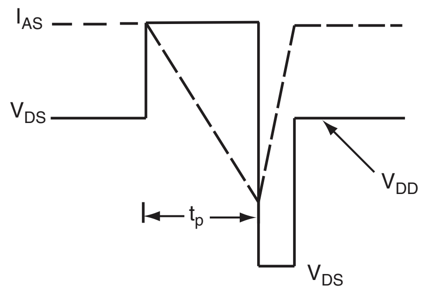


Fig. 12b - Unclamped Inductive Waveforms

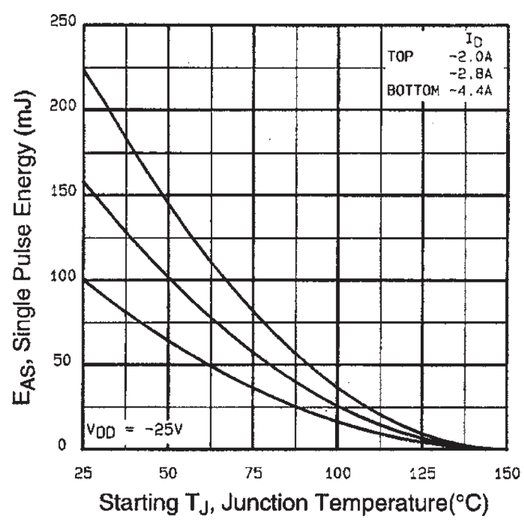


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

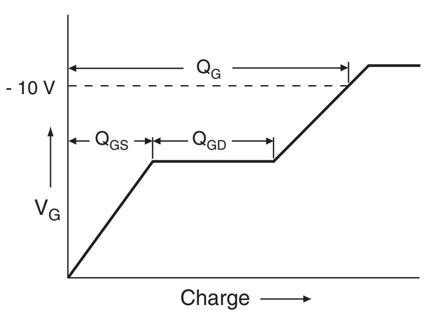


Fig. 13a - Basic Gate Charge Waveform

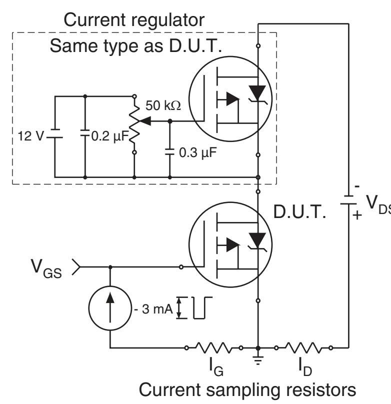
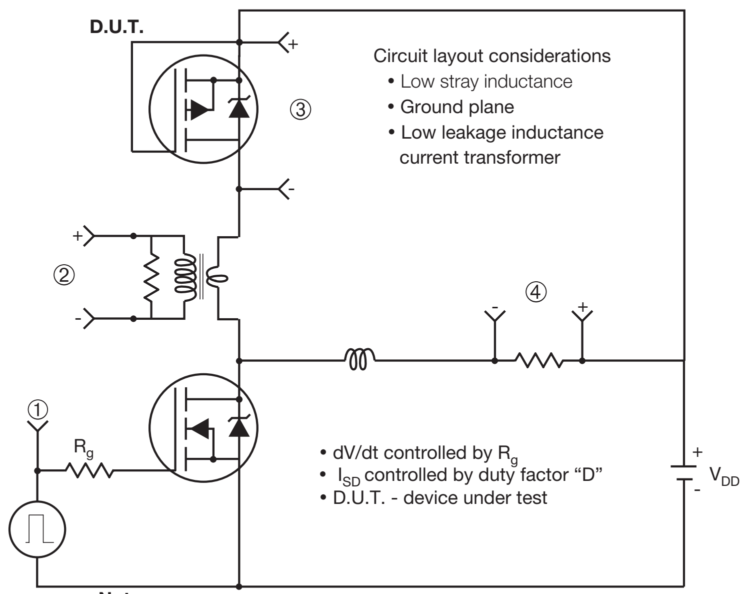


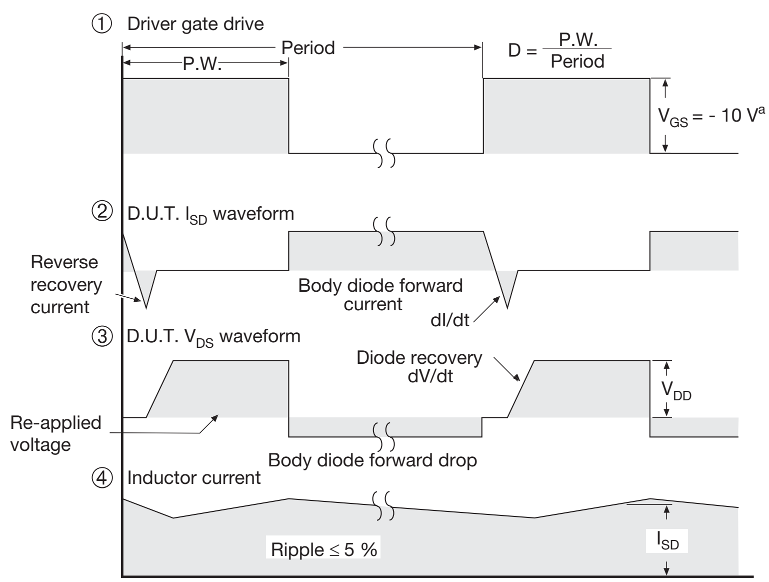
Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



Note

• Compliment N-Channel of D.U.T. for driver



Note

a. V_{GS} = - 5 V for logic level and - 3 V drive devices

Fig. 14 - For P-Channel

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